

### SEMiX<sup>®</sup> 3p

### Trench IGBT Modules

#### SEMiX603GB12E4p

#### Features

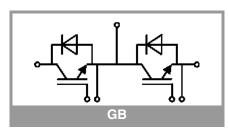
- Homogeneous Si
- Trench = Trenchgate technology
  V<sub>CE(sat)</sub> with positive temperature
- coefficient
- High short circuit capability
- Press-fit pins as auxiliary contacts
   Thermally actimized example
- Thermally optimized ceramicUL recognized, file no. E63532

### Typical Applications\*

- AC inverter drives
- UPS
- Renewable energy systems

#### Remarks

- Product reliability results are valid for  $T_i=150^{\circ}C$
- V<sub>isol</sub> between temperature sensor and power section is only 2500V
- For storage and case temperature with TIM see document "TP(\*) SEMiX 3p"



Absolut	e Maximum Ratin	igs		
Symbol	Conditions		Values	Unit
IGBT				
V <sub>CES</sub>	T <sub>j</sub> = 25 °C		1200	V
lc	T <sub>j</sub> = 175 °C	T <sub>c</sub> = 25 °C	1110	А
		T <sub>c</sub> = 80 °C	853	А
I <sub>Cnom</sub>			600	А
I <sub>CRM</sub>	I <sub>CRM</sub> = 3xI <sub>Cnom</sub>		1800	А
V <sub>GES</sub>			-20 20	V
t <sub>psc</sub>	$V_{CC} = 800 V$ $V_{GE} \le 15 V$ $V_{CES} \le 1200 V$	T <sub>j</sub> = 150 °C	10	μs
Tj			-40 175	°C
Inverse	diode			
V <sub>RRM</sub>	T <sub>i</sub> = 25 °C		1200	V
l <sub>F</sub>	T <sub>j</sub> = 175 °C	T <sub>c</sub> = 25 °C	856	Α
		T <sub>c</sub> = 80 °C	640	А
<b>I</b> <sub>Fnom</sub>			600	A
I <sub>FRM</sub>	I <sub>FRM</sub> = 3xI <sub>Fnom</sub>		1800	А
I <sub>FSM</sub>	t <sub>p</sub> = 10 ms, sin 180°, T <sub>j</sub> = 25 °C		3456	А
Tj			-40 175	°C
Module				<b>.</b>
I <sub>t(RMS)</sub>			600	А
T <sub>stg</sub>	module without TIM		-40 125	°C
V <sub>isol</sub>	AC sinus 50Hz, t = 1 min		4000	V

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
IGBT						
V <sub>CE(sat)</sub>	$I_{\rm C} = 600  {\rm A}$	T <sub>j</sub> = 25 °C		1.80	2.05	V
	V <sub>GE</sub> = 15 V chiplevel	T <sub>j</sub> = 150 °C		2.03	2.30	V
V <sub>CE0</sub>	chiplevel	T <sub>j</sub> = 25 °C		0.87	1.01	V
		T <sub>j</sub> = 150 °C		0.77	0.90	V
r <sub>CE</sub>	V <sub>GE</sub> = 15 V chiplevel	T <sub>j</sub> = 25 °C		1.55	1.73	mΩ
		T <sub>j</sub> = 150 °C		2.1	2.3	mΩ
V <sub>GE(th)</sub>	$V_{GE} = V_{CE}, I_C = 22.2 \text{ mA}$		5.3	5.8	6.3	V
I <sub>CES</sub>	$V_{GE} = 0 V, V_{CE} = 12$	00 V, T <sub>j</sub> = 25 °C			5	mA
Cies		f = 1 MHz		37.5		nF
Coes	V <sub>CE</sub> = 25 V V <sub>GE</sub> = 0 V	f = 1 MHz		2.31		nF
C <sub>res</sub>		f = 1 MHz		2.04		nF
Q <sub>G</sub>	V <sub>GE</sub> = - 8 V+ 15 V			3450		nC
R <sub>Gint</sub>	T <sub>j</sub> = 25 °C			1.2		Ω
t <sub>d(on)</sub>	$di/dt_{on} = 6400 \text{ A/}\mu\text{s}$ $di/dt_{off} = 4150 \text{ A/}\mu\text{s}$	T <sub>j</sub> = 150 °C		260		ns
t <sub>r</sub>		T <sub>j</sub> = 150 °C		85		ns
Eon		T <sub>j</sub> = 150 °C		69		mJ
t <sub>d(off)</sub>		T <sub>j</sub> = 150 °C		560		ns
t <sub>f</sub>		T <sub>j</sub> = 150 °C		145		ns
E <sub>off</sub>		T <sub>j</sub> = 150 °C		80		mJ
R <sub>th(j-c)</sub>	per IGBT				0.037	K/W
R <sub>th(c-s)</sub>	per IGBT (λ <sub>grease</sub> =0.81 W/(m*K))			0.035		K/W
R <sub>th(c-s)</sub>	per IGBT, pre-appli material		0.025		K/W	



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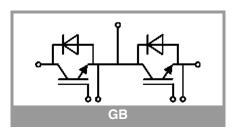
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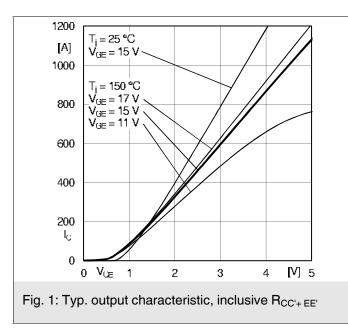
- AC inverter drives
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- Renewable energy systems

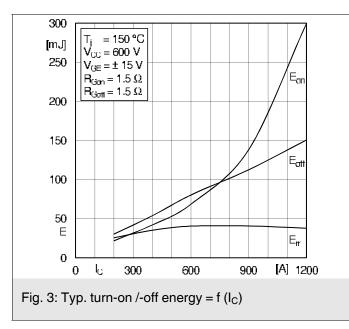
#### Remarks

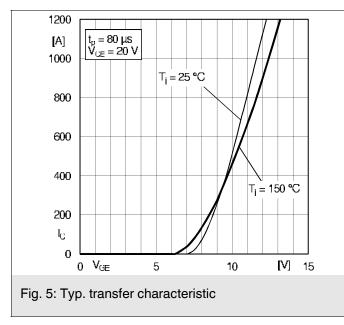
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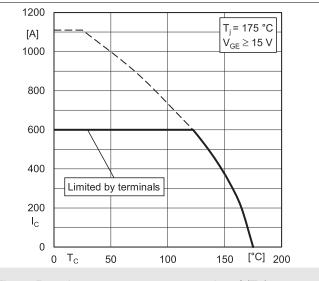
Characte	ristics					
Symbol	Conditions	min.	typ.	max.	Unit	
Inverse di	iode					
$V_F = V_{EC}$	$I_{\rm F} = 600  {\rm A}$	T <sub>j</sub> = 25 °C		2.08	2.44	V
	V <sub>GE</sub> = 0 V chiplevel	T <sub>j</sub> = 150 °C		2.08	2.34	V
V <sub>F0</sub>	chiplevel	T <sub>j</sub> = 25 °C		1.39	1.59	V
		T <sub>j</sub> = 150 °C		1.08	1.18	V
r <sub>F</sub>	chiplevel	T <sub>j</sub> = 25 °C		1.16	1.42	mΩ
		T <sub>j</sub> = 150 °C		1.67	1.93	mΩ
I <sub>RRM</sub>	I <sub>F</sub> = 600 A di/dt <sub>off</sub> = 5100 A/μs V <sub>GE</sub> = -15 V	T <sub>j</sub> = 150 °C		475		А
Q <sub>rr</sub>		T <sub>j</sub> = 150 °C		108		μC
E <sub>rr</sub>	$V_{CC} = 600 V$	T <sub>j</sub> = 150 °C		40		mJ
R <sub>th(j-c)</sub>	per diode				0.065	K/W
R <sub>th(c-s)</sub>	per diode ( $\lambda_{grease}=0$	.81 W/(m*K))		0.039		K/W
R <sub>th(c-s)</sub>	per diode, pre-applied phase change material			0.031		K/W
Module						1
L <sub>CE</sub>				20		nH
R <sub>CC'+EE'</sub>	measured per	T <sub>C</sub> = 25 °C		1.2		mΩ
	switch	T <sub>C</sub> = 125 °C		1.65		mΩ
Rth <sub>(c-s)1</sub>	calculated without thermal coupling			0.009		K/W
Rth <sub>(c-s)2</sub>	including thermal co Ts underneath mod (m*K))		0.014		K/W	
Rth <sub>(c-s)2</sub>	including thermal coupling, Ts underneath module, pre-applied phase change material			0.011		K/W
Ms	to heat sink (M5)		3		6	Nm
Mt		to terminals (M6)	3		6	Nm
						Nm
w					350	g
Temperat	ure Sensor					
R <sub>100</sub>	T <sub>c</sub> =100°C (R <sub>25</sub> =5 kΩ)			493 ± 5%		Ω
B <sub>100/125</sub>	$R_{(T)}=R_{100}exp[B_{100/125}(1/T-1/T_{100})];T[K];$			3550 ±2%		к

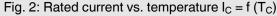


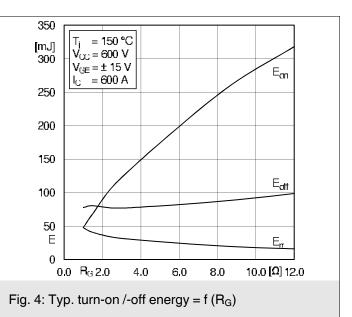


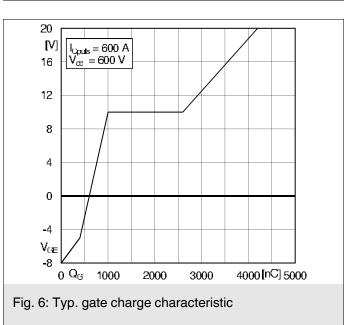




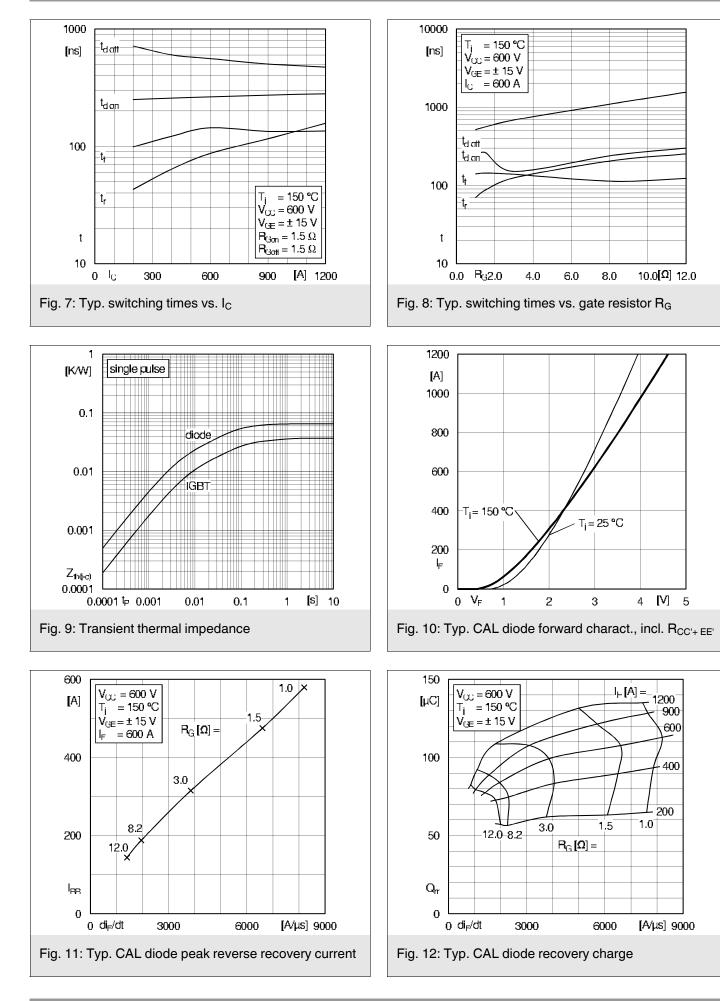






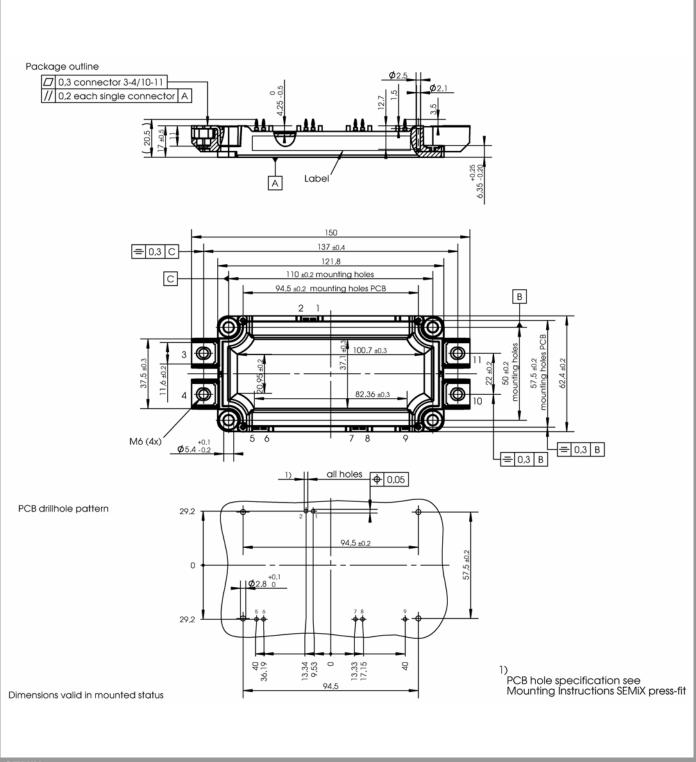


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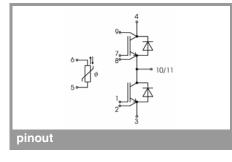


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This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, chapter IX.

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